IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Group Art Unit: To Be Assigned Examiner: To Be Assigned

In re PATENT APPLICATION of

Applicant(s) : Masashi SANO

Appln. No. : To Be Assigned

Filed : June 30, 2003) INFORMATION) DISCLOSURE STATEMENT

For : REFLECTIVE SENSOR, FILTER FOR

REFLECTIVE SENSOR, AND METHOD)
OF DETECTING OBJECT USING THE)
SAME)

Atty. Dkt. : AI 287

Commissioner for Patents Washington, D.C. 20231

Sir:

This is an information disclosure statement submitted in compliance with the timing requirements of 37 C.F.R. §1.97(b)(1).

Attached are copies of one Japanese patent publication and one Japanese utility model publication. The relevance of the Japanese publication can be gleaned from the attached English-language Abstract. The documents are listed on the attached Form PTO-1449.

Since this Information Disclosure Statement is being filed with the application, no certification or fee is required, and the requirements of 37 C.F.R. §§1.97 and 1.98 are deemed to be fully met as to the documents submitted. Consideration of the submitted documents is respectfully requested.

Respectfully submitted,

June 30, 2003

Date Steven M. Rabin (Reg. No. 29,102)

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				Applicant Masashi SANO				
				Filing Date Group Unit				
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